

TEST REPORT

Applicant Name: Anker Japan Co., Ltd.
Address: 9F Waterras Tower, 2-101, Kanda-Awajicho, Chiyoda-ku, Tokyo
Report Number: 2501A32937E-RF-07

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: SmartTrack Card E40
Model No.: T87B3
Multiple Model(s) No.: N/A
Trade Mark: eufy
Date Received: 2025-12-24
Issue Date: 2026-01-13

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Ekko Wu

Ekko Wu
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.
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Bay Area Compliance Laboratories Corp. (Shenzhen)

5F(B-West), 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China
Tel: +86-755-33320018 Fax: +86-755-33320008 www.baclcorp.com.cn

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501A32937E-RF-07	Original Report	2026-01-13

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	BLE
	Modulation Type	GFSK
	Frequency Range	2402-2480MHz
	Rated Output Power	4 .0mW for BLE 1M/BLE 2M
	Antenna Gain[#]	1.41dBi (It is provided by the applicant)
Nominal Power Supply		DC 3.85V from battery
Sample serial number		3F28-1 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 of Jan. 26, 2004, Appendix No.43 (Latest version: MIC Notice No.373 of Nov. 8, 2023)

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency error	81.235Hz(k=1.96, 95% level of confidence)
Occupied Channel Bandwidth	52.29kHz(k=1.96, 95% level of confidence)
RF output power, conducted	1.57dB(k=1.96, 95% level of confidence)
Unwanted Emission, conducted	2.48dB(k=1.96, 95% level of confidence)
Duty Cycle	±1%
Temperature	±0.4°C
Supply voltages	DC±0.4%;AC±1%
Humidity	±2%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode by some software.

For BLE mode, 40 channels are provided for testing:

Channel	Frequency(MHz)	Channel	Frequency(MHz)
0	2402	20	2442
1	2404	21	2444
...	...	...	...
...	...	...	...
...	...	...	...
18	2438	38	2478
19	2440	39	2480

EUT was tested with channel 0, 19 and 39.

Normal/Extreme Voltage Condition[#]

NV	Normal Voltage	3.85V _{DC}
LV	Low Voltage	3.47V _{DC}
HV	High Voltage	4.24V _{DC}

Note: extreme voltage test conditions were declared by manufacturer.

The EUT works with a battery, power deviation of the RF circuit is less than 1% when extreme voltage supplied, therefore the test only performed at normal condition.

EUT Exercise Software

Exercise Software#	GRDirect Test Mode Tool.exe		
Power Level#			
Mode	Low Channel	Middle Channel	High Channel
BLE 1M	5	5	5
BLE 2M	5	5	5

Equipment Modifications

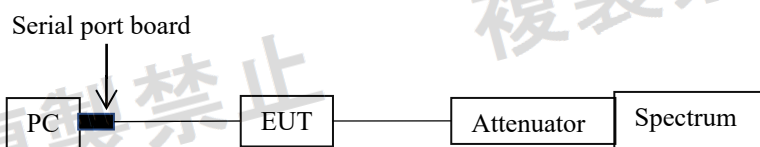
No modification was made to the EUT tested.

Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
Unknown	Serial port board	Unknown	Unknown
DELL	PC	DESKTOP-1630AQ3	Unknown

External I/O Cable

Cable Description	Length(m)	From/Port	To
Dupont cable	0.3	Serial port board	EUT

Configuration of Test Setup

SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Carrier sense capability	Not Applicable**
8	Transmission Radiation Angle Width	Not Applicable
9	Frequency Hopping Dwell Time	Not Applicable*
10	Interference Prevention Function	Compliant
11	Construction Protection Confirmation	Compliant

Not Applicable* -Testing is only required for FHSS system devices.

Not Applicable**-The OBW of EUT is less than 26 MHz.

Not Applicable - This test item was not required for the output power less than 12.14 dBm (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Rohde & Schwarz	Spectrum Analyzer	FSU26	200982	2025/08/12	2026/08/11	BACL Cal	c)
ANRITSU	Microwave peak power sensor	MA24418A	12622	2025/09/01	2026/08/31	CCIC	c)
Rohde & Schwarz	Wideband Radio Communication Tester	CMW500	146520	2025/09/18	2026/09/17	CCIC	c)
JD	JD Auto Test software	NA	1.0.0.3769	NCR	NCR	/	/
instek	DC Power Supply	GPS-3030DD	EM832096	NCR	NCR	/	/
Fluke	Digital Multimeter	287	19000011	2025/04/29	2026/04/28	BACL Cal	c)
Unknown	10dB Attenuator	Unknown	F-03-EM190	2025/06/26	2026/06/25	BACL SZ	d)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

Frequency Error

Limit

50 ppm or below

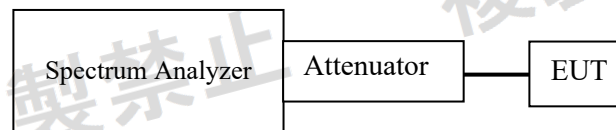
Test Procedure

Set the EUT to the measurement frequency without modulation.
Setting of SA is following as:

- Center Frequency: Frequency to measure
- RBW: 1 kHz, VBW: 3 kHz
- Span: 300 kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

Record the peak spot frequency.

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.



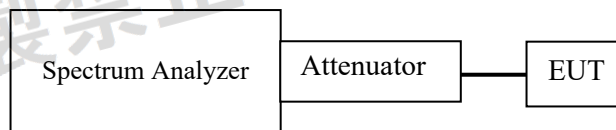
Occupied Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz

Test Procedure

1. Setting of SA is following as:
 - Center Frequency: Frequency to measure
 - RBW: 30 kHz, VBW: 30 kHz
 - Sweep time: Auto
 - Log scale: 10dB/Div, Data points: 400 points or more
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak
 - Sweep mode: Continuous Sweep
 - Marker: Spot
2. EUT have transmitted the maximum modulation signal and fixed channelize. SA set to 99% of occupied bandwidth to measure occupied bandwidth.



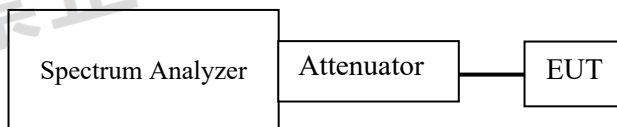
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto (Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Note: $2.5 \mu\text{W/MHz} = 0.25 \mu\text{W}/100\text{kHz}$

Antenna Output Power and Antenna Power Tolerance

Limit

Antenna power:

- $\leq 10 \text{ mW/MHz}$ (OFDM, DSSS from 2400-2483.5 MHz)
- $\leq 10 \text{ mW}$ (other from 2400-2483.5 MHz)

The Output Power Tolerance must be within +20%, -80%.

E.i.r.p:

- $\leq 12.14 \text{ dBm/MHz}$ (OFDM (20MHz system), DSSS form 2400-2483.5MHz)
- $\leq 9.13 \text{ dBm/MHz}$ (OFDM(40MHz system) from 2400-2483.5MHz)
- $\leq 12.14 \text{ dBm}$ (other from 2400-2483.5MHz)

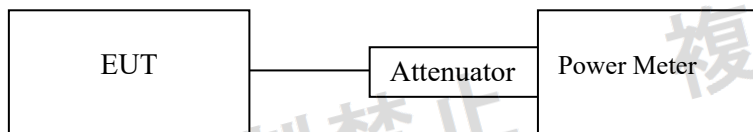
Test Procedure

Step 1: Measure the total power by Power Meter

Step 2: If it's the burst wave, set the power meter to measure averaging across the burst transmit on period.

Step 3: Record the reading on power meter as antenna output power.

Test Setup Block diagram



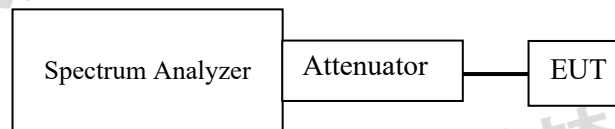
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4\text{nW}$ ($30\text{ MHz} \leq f \leq 1000\text{ MHz}$)
- $\leq 20\text{ nW}$ ($f \geq 1\text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

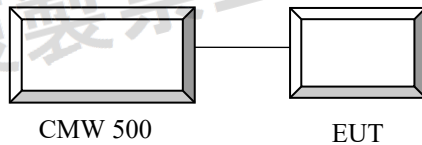
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Test Information:**

Sample No.:	3F28-1	Test Date:	2026/01/05
Test Site:	RF	Test Mode:	Transmitting/Receiving
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.6	Relative Humidity: (%)	49	ATM Pressure: (kPa)	101
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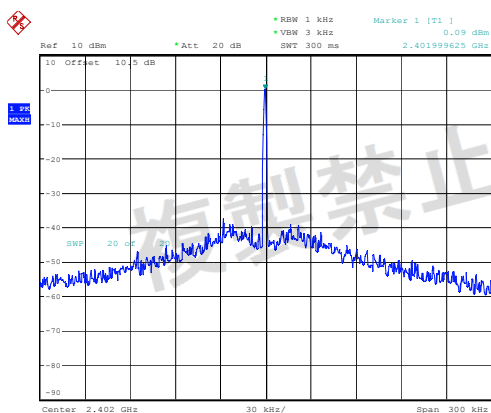
Frequency Error**Test Condition: NV**

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99963	-0.15	± 50	Pass
	2440	2439.99963	-0.15		Pass
	2480	2479.99925	-0.30		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

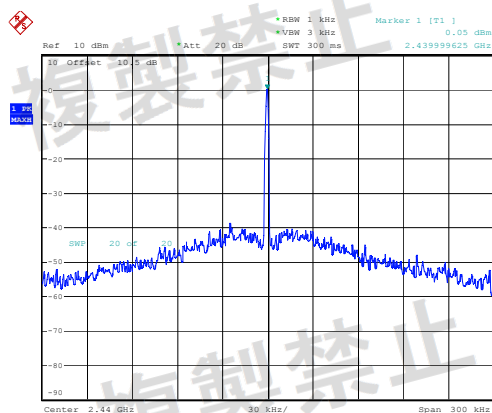
Test Condition: NV

2402MHz



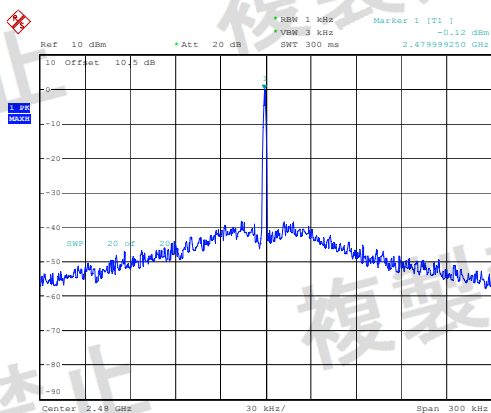
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:57:20

2440MHz



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:57:42

2480MHz



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:58:07

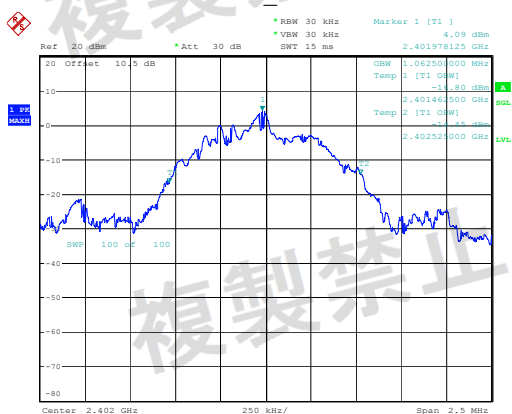
Occupied Bandwidth

Test Condition: NV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.063	1.066	1.097	≤ 26	Pass
BLE 2M	2.056	2.069	2.069		Pass

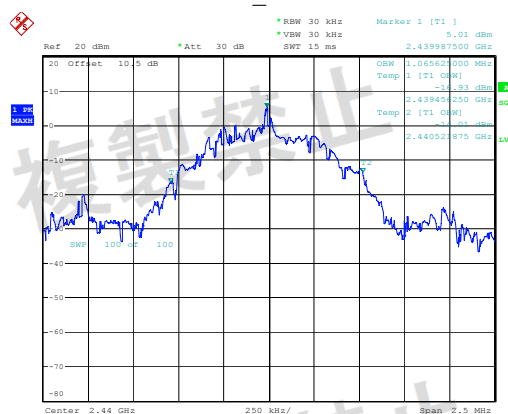
Test Condition: NV

BLE 1M_Low Channel



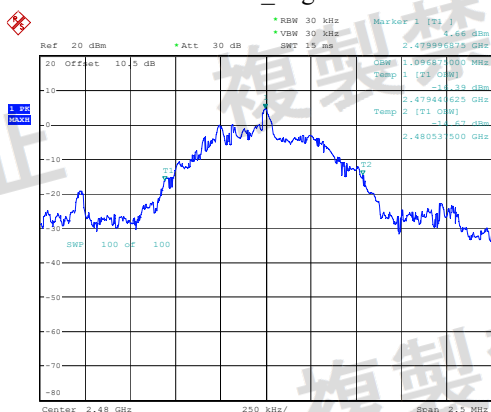
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Date: 5.JAN.2026 15:32:51

BLE 1M_Middle Channel



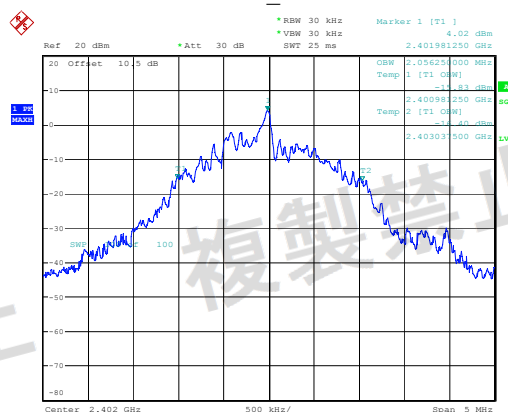
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Date: 5.JAN.2026 15:37:39

BLE 1M_High Channel



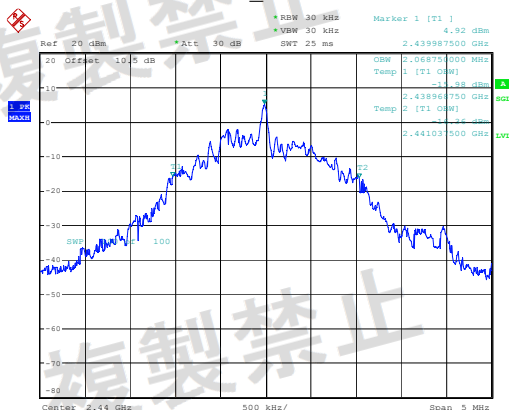
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Date: 5.JAN.2026 15:40:52

BLE 2M_Low Channel



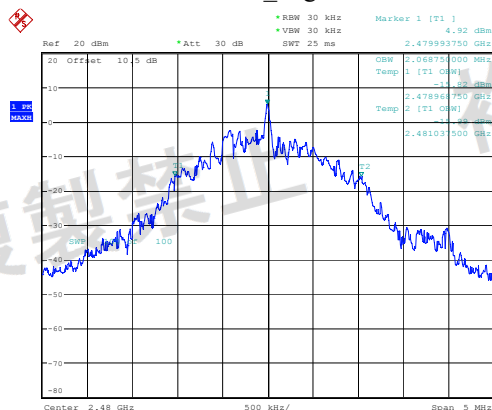
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:44:06

BLE 2M_Middle Channel



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:48:54

BLE 2M_High Channel



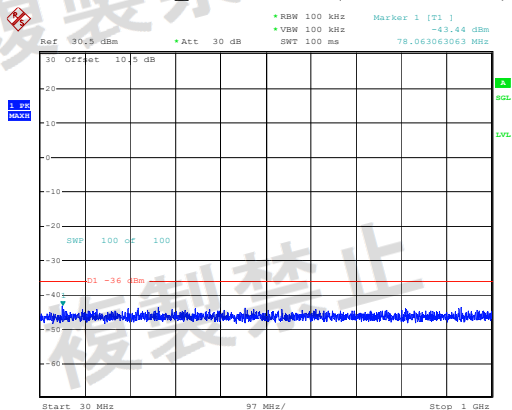
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:53:13

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Condition: Normal, BLE 1M**

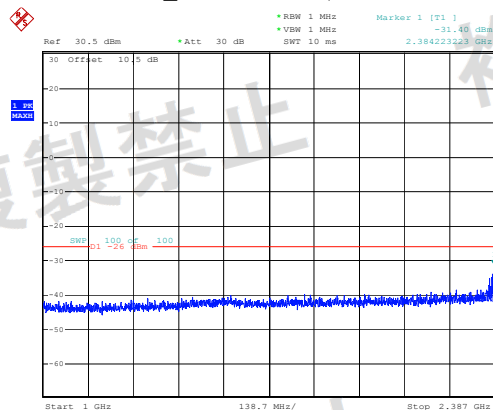
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	78.0630631	-43.44	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	2384.2232000	-31.40	0.724	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9935000	-19.80	10.474	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.2452000	-37.43	0.181	25	Pass
	Band V (1MHz)	2496.5	12500	10752.6419000	-37.21	0.190	2.50	Pass
Middle	Band I (100kHz)	30	1000	673.2682683	-43.64	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2249.5495000	-38.83	0.131	2.50	Pass
	Band III (1MHz)	2387	2400	2398.0480000	-36.31	0.234	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5260000	-35.71	0.269	25	Pass
	Band V (1MHz)	2496.5	12500	12104.4662000	-36.44	0.227	2.50	Pass
High	Band I (100kHz)	30	1000	490.2402402	-43.45	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	2205.8153000	-39.54	0.111	2.50	Pass
	Band III (1MHz)	2387	2400	2394.3654000	-38.30	0.148	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5065000	-19.00	12.589	25	Pass
	Band V (1MHz)	2496.5	12500	2496.5000	-32.20	0.603	2.50	Pass

Test Condition: Normal, BLE 2M

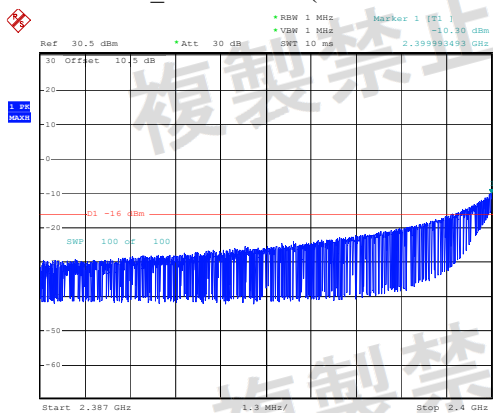
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	81.9469469	-43.70	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2387.000	-32.66	0.542	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9805000	-17.33	18.514	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.3624000	-37.37	0.183	25	Pass
	Band V (1MHz)	2496.5	12500	10717.5946000	-37.11	0.195	2.50	Pass
Middle	Band I (100kHz)	30	1000	934.9449449	-43.89	0.041	0.25	Pass
	Band II (1MHz)	1000	2387	2372.4219000	-37.80	0.166	2.50	Pass
	Band III (1MHz)	2387	2400	2399.8569000	-34.49	0.356	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.8924000	-35.33	0.293	25	Pass
	Band V (1MHz)	2496.5	12500	12064.4122000	-36.76	0.211	2.50	Pass
High	Band I (100kHz)	30	1000	586.8518519	-43.68	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2337.0180000	-38.89	0.129	2.50	Pass
High	Band III (1MHz)	2387	2400	2398.4515000	-37.83	0.165	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5390000	-18.90	12.882	25	Pass
	Band V (1MHz)	2496.5	12500	2496.5000	-31.28	0.745	2.50	Pass

Test Condition: NV**BLE 1M_Low Channel(30MHz~1GHz)**

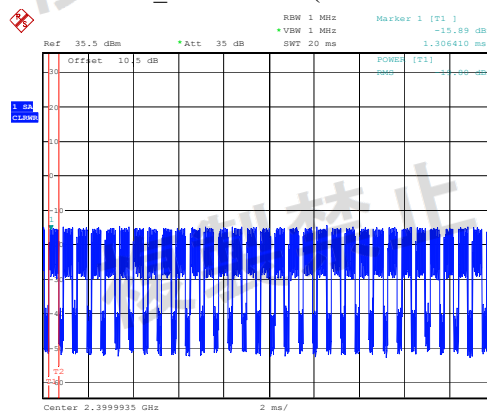
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:33:07

BLE 1M_Low Channel(1GHz~2.387GHz)

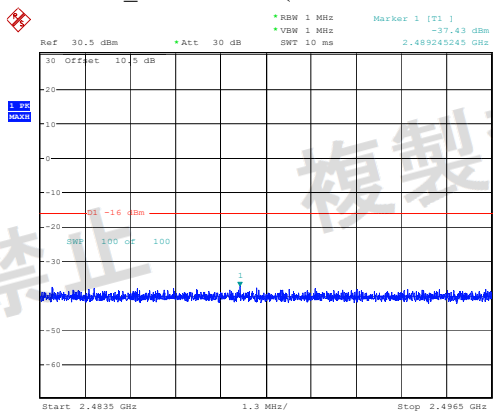
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BLE 1M_Low Channel(2.387GHz~2.4GHz)

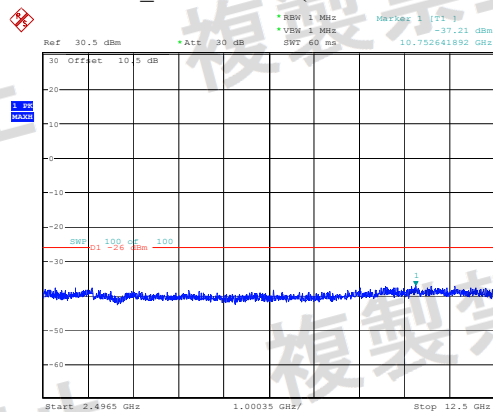
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:33:25

BLE 1M_Low Channel(2.387GHz~2.4GHz)

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Date: 5.JAN.2026 15:35:33

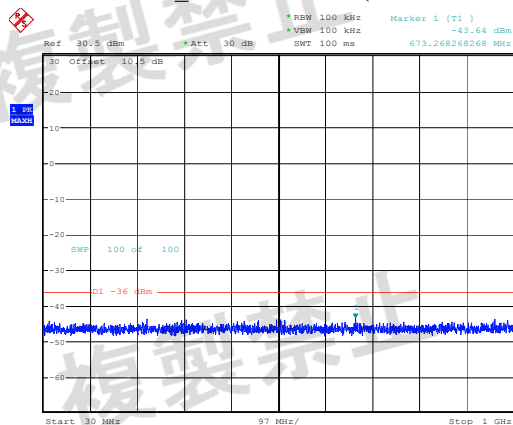
BLE 1M_Low Channel(2.4835GHz~2.4965GHz)

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Date: 5.JAN.2026 15:35:41

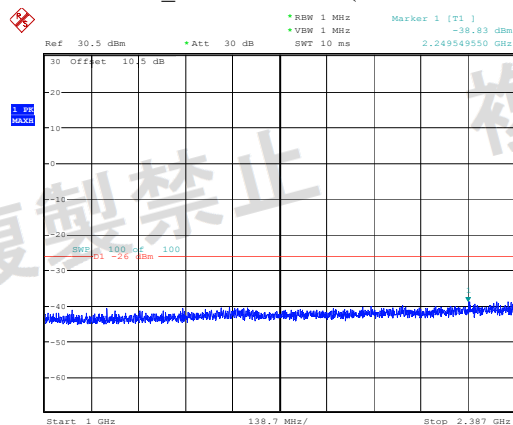
BLE 1M_Low Channel(2.4965GHz~12.5GHz)

ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:36:05

BLE 1M_Middle Channel(30MHz~1GHz)



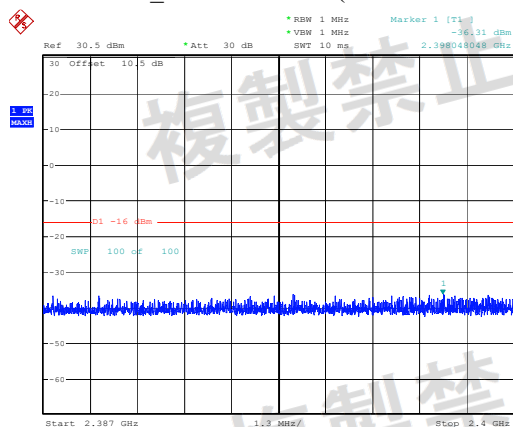
BLE 1M_Middle Channel(1GHz~2.387GHz)



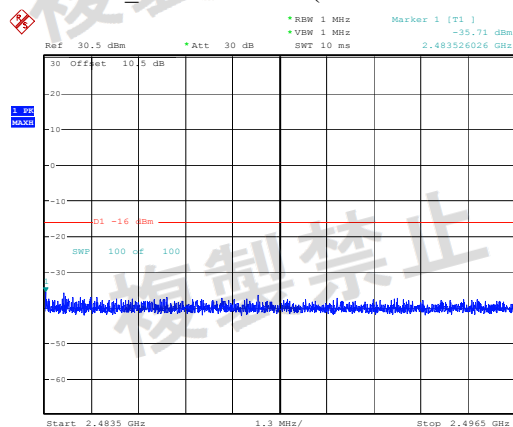
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:37:55

ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:38:05

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



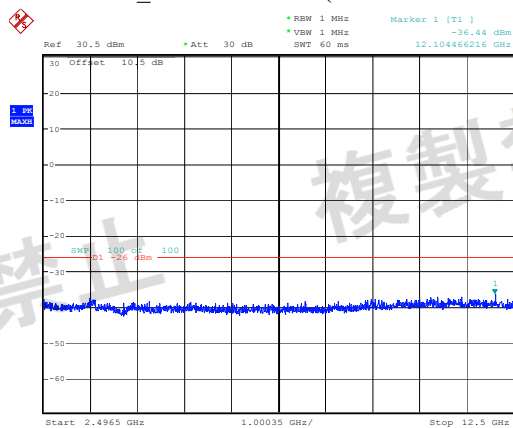
BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



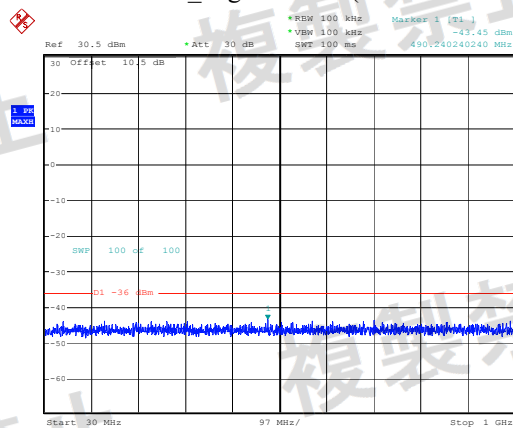
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:38:12

ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:38:20

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



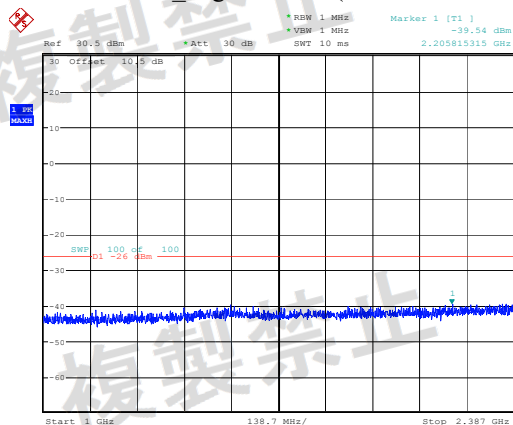
BLE 1M_High Channel(30MHz~1GHz)



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:38:44

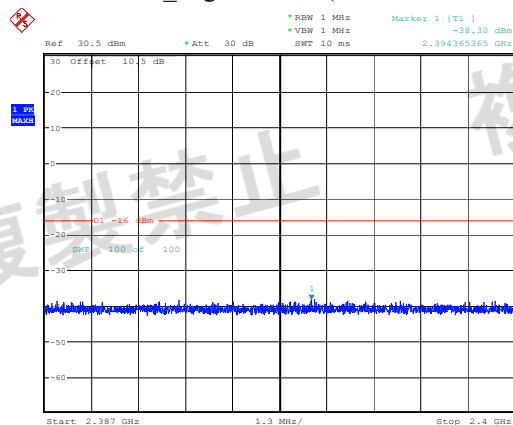
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:41:08

BLE 1M_High Channel(1GHz~2.387GHz)



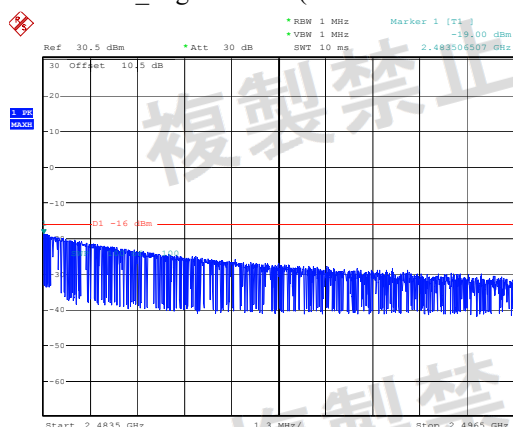
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:41:19

BLE 1M_High Channel(2.387GHz~2.4GHz)



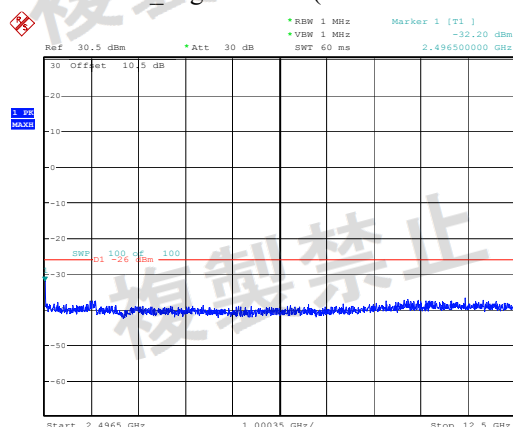
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:41:27

BLE 1M_High Channel(2.4835GHz~2.4965GHz)



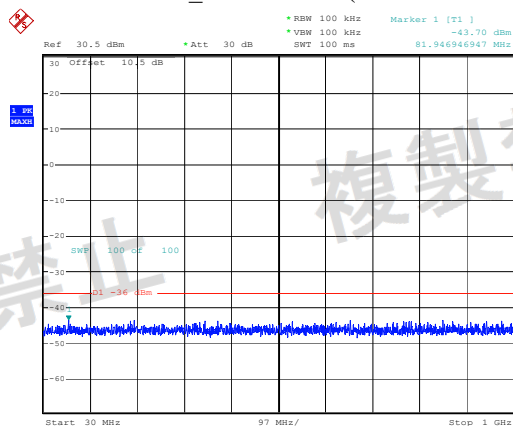
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:41:35

BLE 1M_High Channel(2.4965GHz~12.5GHz)



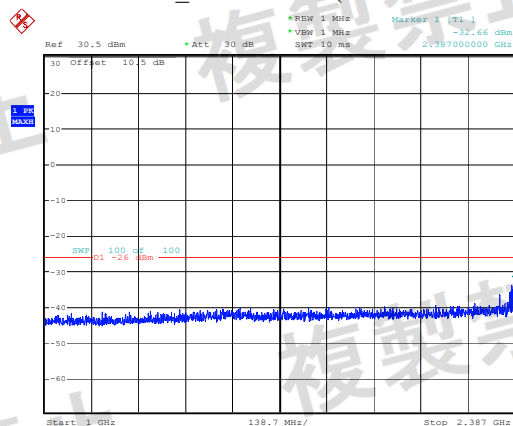
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:42:00

BLE 2M_Low Channel(30MHz~1GHz)



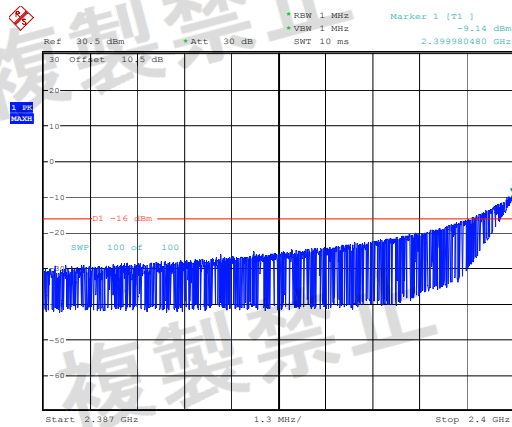
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:44:22

BLE 2M_Low Channel(1GHz~2.387GHz)



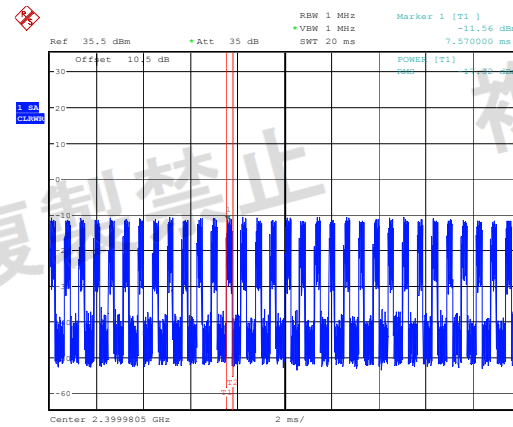
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:44:33

BLE 2M_Low Channel(2.387GHz~2.4GHz)



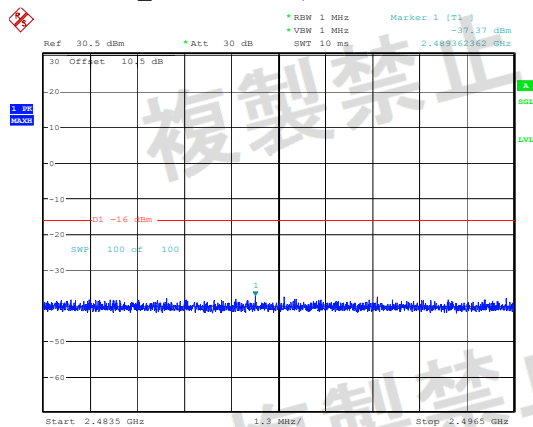
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:44:41

BLE 2M_Low Channel(2.387GHz~2.4GHz)



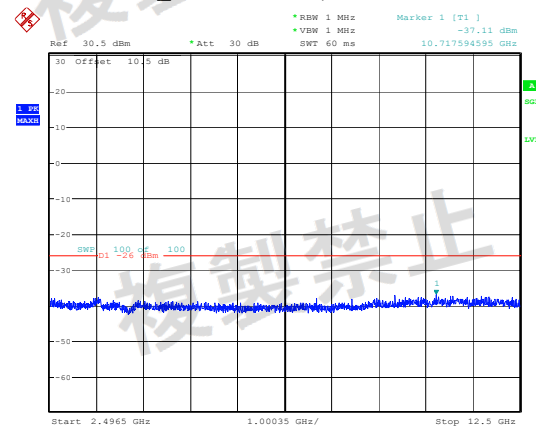
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:46:40

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



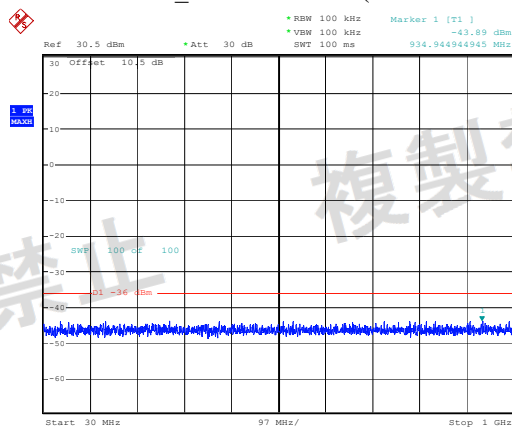
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:46:49

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



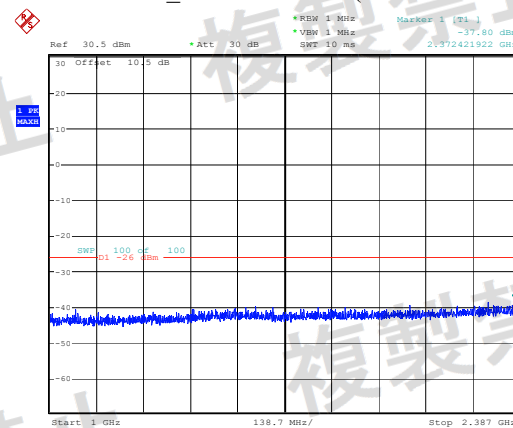
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:47:14

BLE 2M_Middle Channel(30MHz~1GHz)



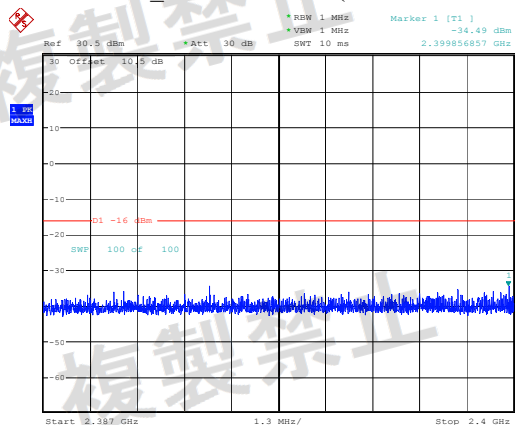
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:49:11

BLE 2M_Middle Channel(1GHz~2.387GHz)



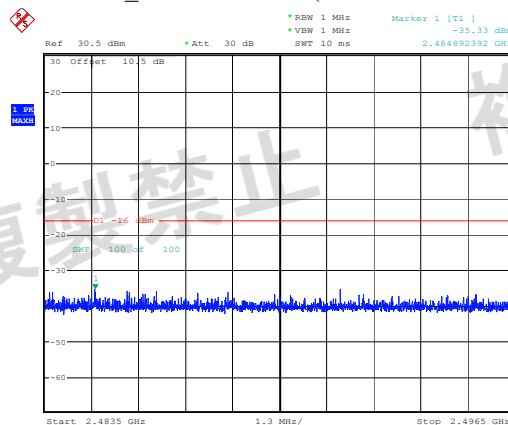
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:49:22

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



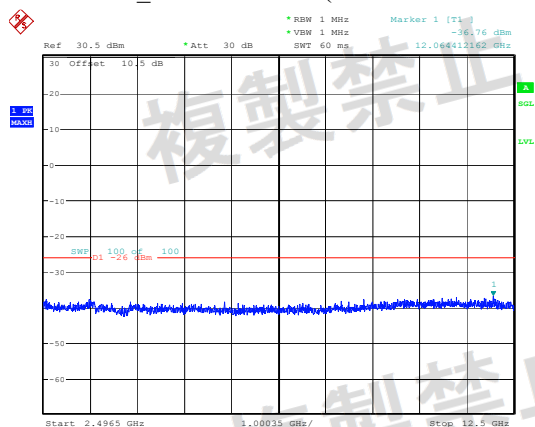
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:49:30

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



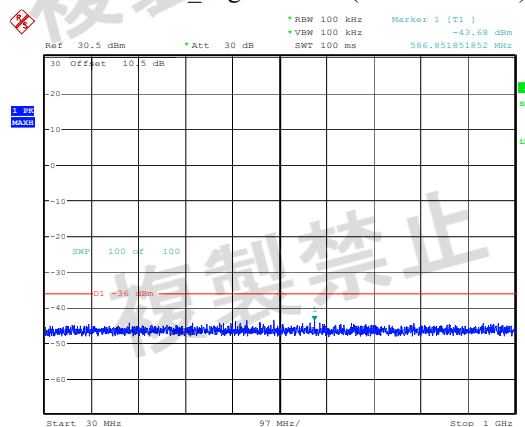
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:49:38

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



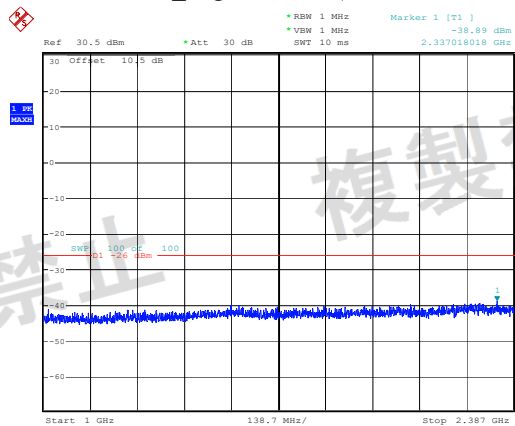
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:50:07

BLE 2M_High Channel(30MHz~1GHz)



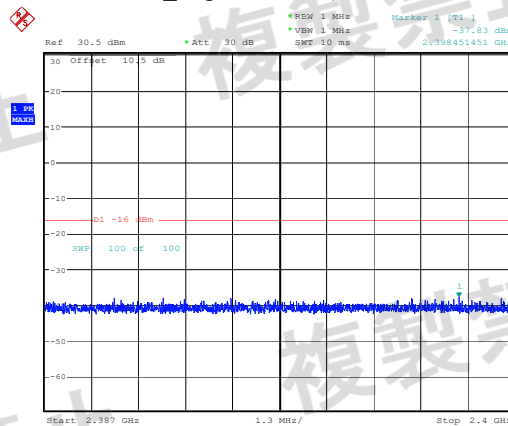
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:53:30

BLE 2M_High Channel(1GHz~2.387GHz)



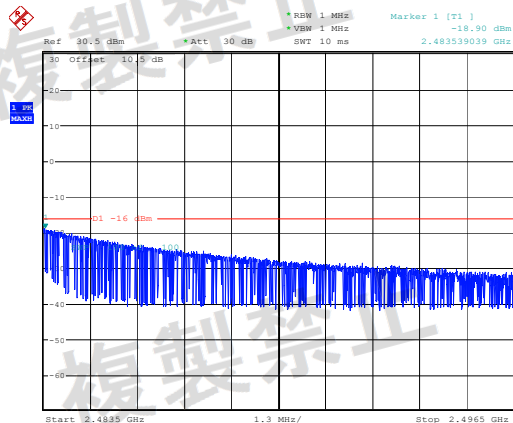
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:53:41

BLE 2M_High Channel(2.387GHz~2.4GHz)



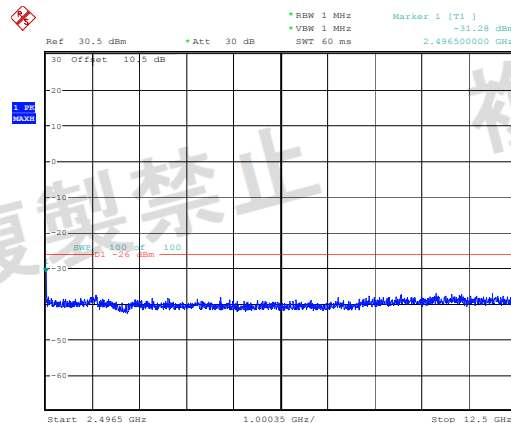
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:53:52

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:54:00

BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:54:26

Antenna Output Power and Output Power Tolerance**Test Condition: NV**

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	1.41	4.0
BLE 2M		4.0

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	5.07	3.214	≤ 10	-19.65	-80~+20	6.48	≤ 12.14	Pass
	Middle	5.14	3.266		-18.35		6.55		Pass
	High	5.06	3.206		-19.85		6.47		Pass
BLE 2M	Low	4.81	3.027	≤ 10	-24.33	-80~+20	6.22	≤ 12.14	Pass
	Middle	4.87	3.069		-23.28		6.28		Pass
	High	4.67	2.931		-26.73		6.08		Pass

Note:

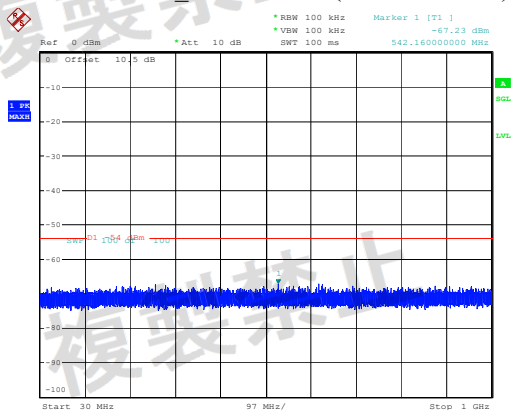
Antenna output power(mW) = $10^{\{\text{Conducted power(dBm)} / 10\}}$

Antenna output power tolerance(%) = (Antenna output power - Declared power) / Declared power * 100%

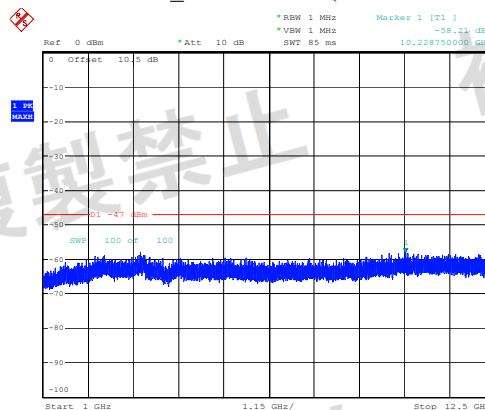
EIRP(dBm) = Conducted power (dBm) + Antenna gain.

Receiver Spurious Emission and Unwanted Emission Intensity**Test Condition: NV**

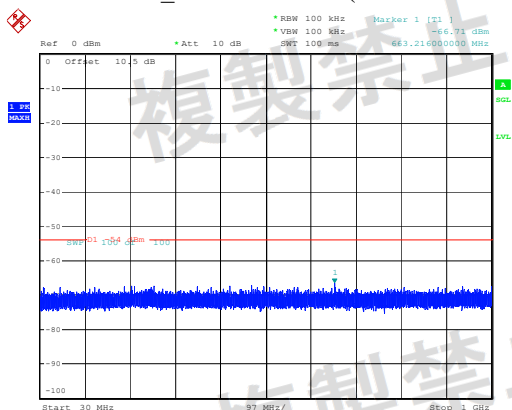
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	542.16	-67.23	0.189	4	Pass
		Band II (1MHz)	1000	12500	10228.75	-58.21	1.510	20	Pass
	Middle	Band I (100kHz)	30	1000	663.216	-66.71	0.213	4	Pass
		Band II (1MHz)	1000	12500	3152.225	-58.17	1.524	20	Pass
	High	Band I (100kHz)	30	1000	227.6375	-67.20	0.191	4	Pass
		Band II (1MHz)	1000	12500	11269.5	-57.40	1.820	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	243.303	-67.22	0.190	4	Pass
		Band II (1MHz)	1000	12500	11866.925	-57.61	1.734	20	Pass
	Middle	Band I (100kHz)	30	1000	206.8795	-66.50	0.224	4	Pass
		Band II (1MHz)	1000	12500	11842.775	-58.37	1.455	20	Pass
	High	Band I (100kHz)	30	1000	991.0275	-66.62	0.218	4	Pass
		Band II (1MHz)	1000	12500	10791.1	-58.23	1.503	20	Pass

Test Condition: NV**BLE 1M_Low Channel(30MHz~1GHz)**

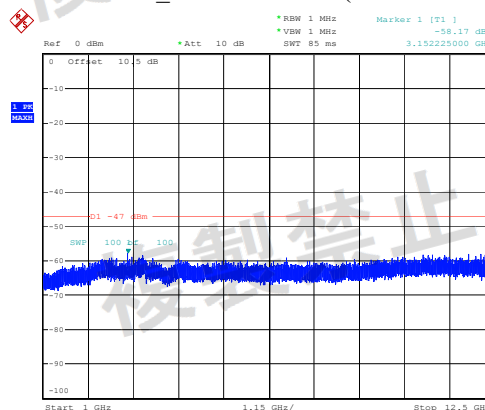
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:58:56

BLE 1M_Low Channel(1GHz~12.5GHz)

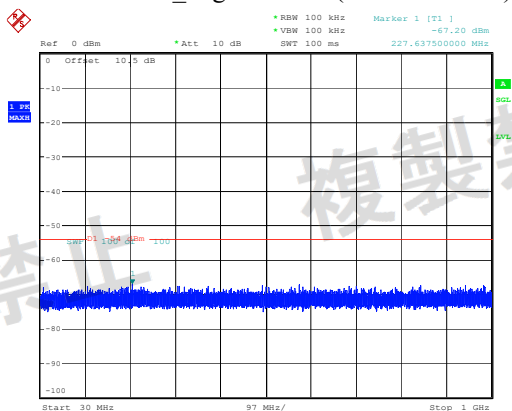
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 15:59:28

BLE 1M_Middle Channel(30MHz~1GHz)

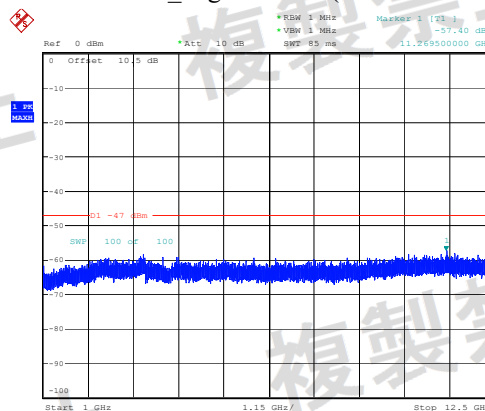
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:01:05

BLE 1M_Middle Channel(1GHz~12.5GHz)

ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:01:36

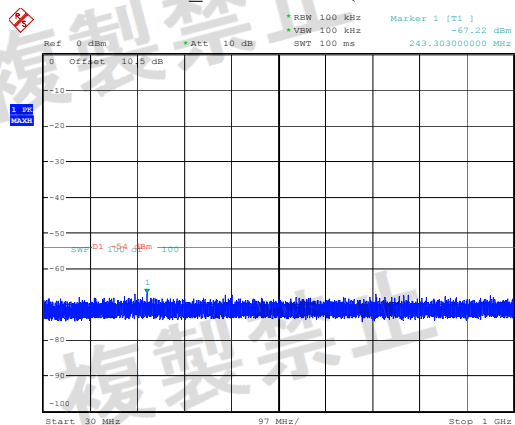
BLE 1M_High Channel(30MHz~1GHz)

ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:02:10

BLE 1M_High Channel(1GHz~12.5GHz)

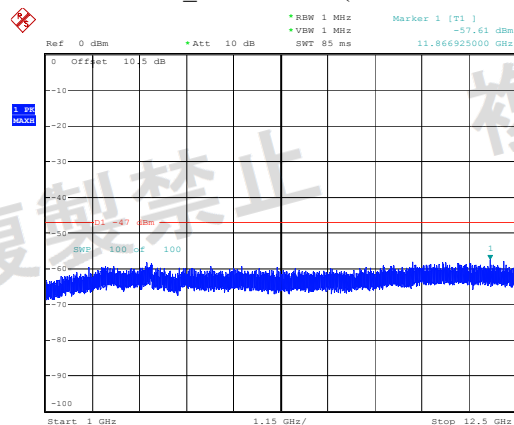
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:02:42

BLE 2M_Low Channel(30MHz~1GHz)



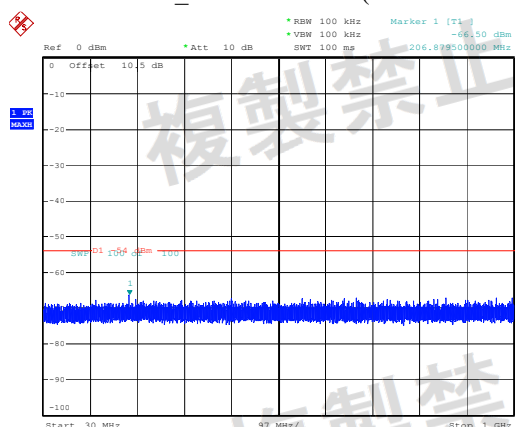
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:03:09

BLE 2M_Low Channel(1GHz~12.5GHz)



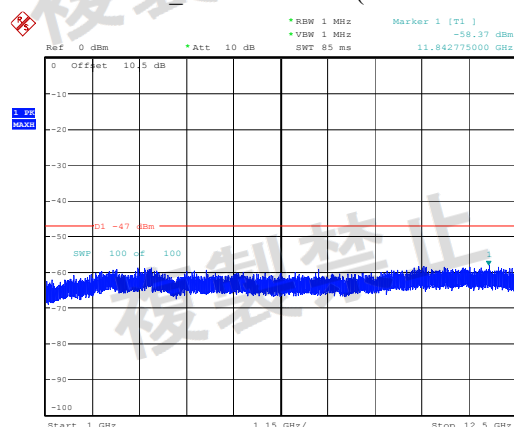
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:03:40

BLE 2M_Middle Channel(30MHz~1GHz)



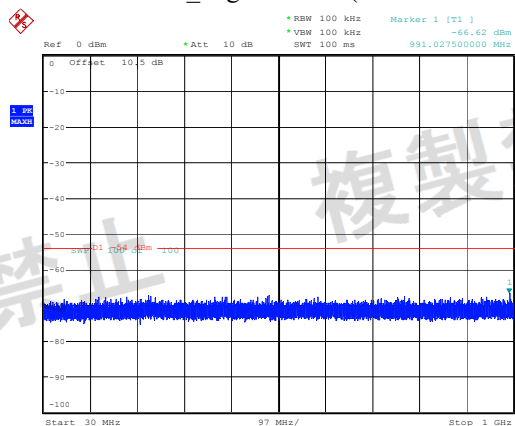
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:04:08

BLE 2M_Middle Channel(1GHz~12.5GHz)



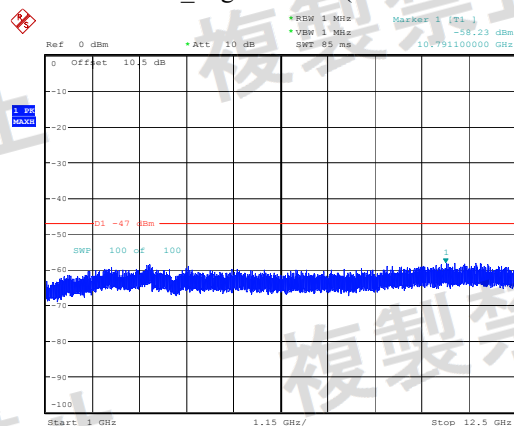
ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:04:40

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:05:30

BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501A32937E-RF Tester:Cheeb Huang
Date: 5.JAN.2026 16:06:02

Interference Prevention Function**Test Information:**

Sample No.:	3F28-1	Test Date:	2026/01/05
Test Site:	RF	Test Mode:	Communicating
Tester:	Cheeb Huang	Test Result:	Good

Environmental Conditions:

Temperature: (°C)	25.6	Relative Humidity: (%)	49	ATM Pressure: (kPa)	101
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CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The product shell was stick together by using some special process, so the device can't be opened easily. Please refer the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501A32937E-RF-EXP External photo and 2501A32937E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501A32937E-RF-07-TSP Test Setup photo.

****END OF REPORT****